TOSHIBA 2SJ338

#### TOSHIBA FIELD EFFECT TRANSISTOR SILICON P CHANNEL MOS TYPE

# 2 S J 3 3 8

#### AUDIO FREQUENCY POWER AMPLIFIER APPLICATION

High Breakdown Voltage  $: V_{DSS} = -180V$ 

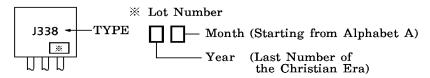
High Forward Transfer Admittance :  $|Y_{fs}| = 0.7S$  (Typ.)

Complementary to 2SK2162

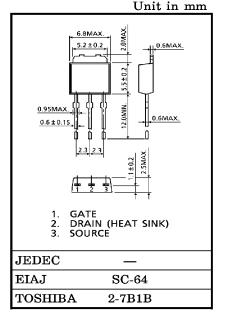
#### MAXIMUM RATINGS (Ta = 25°C)

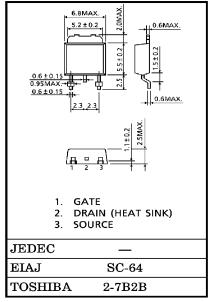
CHARACTERISTIC	SYMBOL	RATING	UNIT
Drain-Source Voltage	${ m v_{DSS}}$	-180	V
Gate-Source Voltage	$v_{GSS}$	±20	V
Drain Current	$I_{\mathbf{D}}$	-1	Α
Power Dissipation (Tc=25°C)	$P_{\mathbf{D}}$	20	W
Channel Temperature	$\mathrm{T_{ch}}$	150	°C
Storage Temperature Range	$\mathrm{T_{stg}}$	-55~150	°C

#### MARKING



## INDUSTRIAL APPLICATIONS





Weight: 0.36g

961001EAA2

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### ELECTRICAL CHARACTERISTICS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Gate Leakage Current	$_{ m IGSS}$	$V_{DS} = 0, V_{GS} = \pm 20V$	_	_	±100	nA
Drain-Source Breakdown Voltage	V <sub>(BR)</sub> DSS	$I_D = -10 \text{mA}, V_{GS} = 0$	-180	_	_	v
Gate -Source Cut-off Current	VGS (OFF) (Note)	$V_{DS} = -10V, I_D = -10mA$	-0.8	_	-2.8	v
Drain-Source Saturation Voltage	V <sub>DS</sub> (ON)	$I_D = -0.6A, V_{GS} = -10V$	_	-1.2	-3.0	v
Forward Transfer Admittance	Y <sub>fs</sub>	$V_{DS} = -10V, I_D = -0.3A$	_	0.7	_	s
Input Capacitance	$C_{iss}$	$V_{DS} = -10V, V_{GS} = 0, f = 1MHz$	_	210	_	pF
Output Capacitance	$C_{oss}$	$V_{DS} = -10V, V_{GS} = 0, f = 1MHz$	_	90	_	pF
Reverse Transfer Capacitance	$\mathrm{c}_{\mathrm{rss}}$	$V_{DS} = -10V, V_{GS} = 0, f = 1MHz$	_	45	_	рF

(Note) VGS (OFF) Classification O :  $-0.8 \sim -1.6$ , Y :  $-1.4 \sim -2.8$ 

This transistor is the electrostatic sensitive device. Plese handle with caution.